

C3M0025065J1

Silicon Carbide Power MOSFET

C3M™ MOSFET Technology

N-Channel Enhancement Mode

Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{rr})
- Halogen free, RoHS compliant

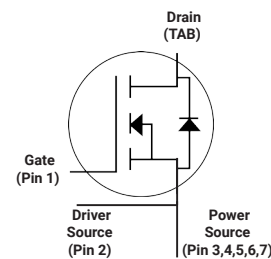
Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

Applications

- Datacenter and Telecom Power Supplies
- EV Battery Chargers
- High voltage DC/DC converters
- Energy Storage Systems
- Solar Inverters

Package



| Part Number | Package | Marking |
|--------------|--------------|--------------|
| C3M0025065J1 | TO-263-7L XL | C3M0025065J1 |

Maximum Ratings ($T_c=25^\circ\text{C}$, unless otherwise specified)

| Symbol | Parameter | Value | Unit | Note |
|----------------|--|-------------|------------------|---------|
| V_{DSmax} | Drain - Source Voltage | 650 | V | |
| V_{GSmax} | Gate - Source voltage | -8/+19 | V | Note 1 |
| I_D | Continuous Drain Current, $V_{GS} = 15\text{ V}$, $T_c = 25^\circ\text{C}$ | 80 | A | Fig. 19 |
| | Continuous Drain Current, $V_{GS} = 15\text{ V}$, $T_c = 100^\circ\text{C}$ | 59 | | |
| $I_{D(pulse)}$ | Pulsed Drain Current, Pulse width t_p limited by T_{jmax} | 251 | A | |
| P_D | Power Dissipation, $T_c=25^\circ\text{C}$, $T_j = 150^\circ\text{C}$ | 271 | W | Fig. 20 |
| T_J, T_{stg} | Operating Junction and Storage Temperature | -40 to +150 | $^\circ\text{C}$ | |
| T_L | Solder Temperature, 1.6mm (0.063") from case for 10s | 260 | $^\circ\text{C}$ | |

Note (1): Recommended turn off / turn on gate voltage $V_{GS} = -4V...0V / +15V$

Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

| Symbol | Parameter | Min. | Typ. | Max. | Unit | Test Conditions | Note |
|---------------|---|------|------|------|---------------|---|--------------|
| $V_{(BR)DSS}$ | Drain-Source Breakdown Voltage | 650 | | | V | $V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$ | |
| V_{GSon} | Gate-Source Recommended Turn-On Voltage | | 15 | | V | Static | |
| V_{GSoff} | Gate-Source Recommended Turn-Off Voltage | | -4 | | V | | |
| $V_{GS(th)}$ | Gate Threshold Voltage | 1.8 | 2.3 | 3.6 | V | $V_{DS} = V_{GS}, I_D = 9.22\ \text{mA}$ | Fig. 11 |
| | | | 2.0 | | V | $V_{DS} = V_{GS}, I_D = 9.22\ \text{mA}, T_J = 150^\circ\text{C}$ | |
| I_{DSS} | Zero Gate Voltage Drain Current | | 1 | 50 | μA | $V_{DS} = 650\ \text{V}, V_{GS} = 0\ \text{V}$ | |
| I_{GSS} | Gate-Source Leakage Current | | 10 | 250 | nA | $V_{GS} = 15\ \text{V}, V_{DS} = 0\ \text{V}$ | |
| $R_{DS(on)}$ | Drain-Source On-State Resistance | | 25 | 34 | m Ω | $V_{GS} = 15\ \text{V}, I_D = 33.5\ \text{A}$ | Fig. 4, 5, 6 |
| | | | 30 | | | $V_{GS} = 15\ \text{V}, I_D = 33.5\ \text{A}, T_J = 150^\circ\text{C}$ | |
| g_{fs} | Transconductance | | 25 | | S | $V_{DS} = 20\ \text{V}, I_{DS} = 33.5\ \text{A}$ | Fig. 7 |
| | | | 24 | | | $V_{DS} = 20\ \text{V}, I_{DS} = 33.5\ \text{A}, T_J = 150^\circ\text{C}$ | |
| C_{iss} | Input Capacitance | | 2980 | | pF | $V_{GS} = 0\ \text{V}, V_{DS} = 0\ \text{V to } 400\ \text{V}$ $F = 1\ \text{MHz}$ $V_{AC} = 25\ \text{mV}$ | Fig. 17, 18 |
| C_{oss} | Output Capacitance | | 178 | | | | |
| C_{rss} | Reverse Transfer Capacitance | | 12 | | | | |
| $C_{o(er)}$ | Effective Output Capacitance (Energy Related) | | 236 | | | | Note: 2 |
| $C_{o(tr)}$ | Effective Output Capacitance (Time Related) | | 340 | | | | Note: 2 |
| E_{oss} | C_{oss} Stored Energy | | 19 | | μJ | $V_{DS} = 400\ \text{V}, F = 1\ \text{MHz}$ | Fig. 16 |
| E_{ON} | Turn-On Switching Energy (Body Diode) | | 116 | | μJ | $V_{DS} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}, I_D = 33.5\ \text{A},$ $R_{G(ext)} = 2.5\ \Omega, L = 59\ \mu\text{H}, T_J = 25^\circ\text{C}$ FWD = Internal Body Diode of MOSFET | Fig. 25 |
| E_{OFF} | Turn Off Switching Energy (Body Diode) | | 59 | | | | |
| $t_{d(on)}$ | Turn-On Delay Time | | 13 | | ns | $V_{DD} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $I_D = 33.5\ \text{A}, R_{G(ext)} = 2.5\ \Omega, L = 59\ \mu\text{H}$ Timing relative to V_{DS} Inductive load | Fig. 26 |
| t_r | Rise Time | | 20 | | | | |
| $t_{d(off)}$ | Turn-Off Delay Time | | 25 | | | | |
| t_f | Fall Time | | 9 | | | | |
| $R_{G(int)}$ | Internal Gate Resistance | | 1.3 | | Ω | $f = 1\ \text{MHz}, V_{AC} = 25\ \text{mV}$ | |
| Q_{gs} | Gate to Source Charge | | 35 | | nC | $V_{DS} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $I_D = 33.5\ \text{A}$ Per IEC60747-8-4 pg 21 | Fig. 12 |
| Q_{gd} | Gate to Drain Charge | | 31 | | | | |
| Q_g | Total Gate Charge | | 109 | | | | |

Note (2): $C_{o(er)}$, a lumped capacitance that gives same stored energy as C_{oss} while V_{ds} is rising from 0 to 400V
 $C_{o(tr)}$, a lumped capacitance that gives same charging time as C_{oss} while V_{ds} is rising from 0 to 400V

Reverse Diode Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

| Symbol | Parameter | Typ. | Max. | Unit | Test Conditions | Note |
|---------------|----------------------------------|------|------|------|--|---------------|
| V_{SD} | Diode Forward Voltage | 5.0 | | V | $V_{GS} = -4\text{ V}, I_{SD} = 16.8\text{ A}, T_J = 25^\circ\text{C}$ | Fig. 8, 9, 10 |
| | | 4.5 | | V | $V_{GS} = -4\text{ V}, I_{SD} = 16.8\text{ A}, T_J = 150^\circ\text{C}$ | |
| I_S | Continuous Diode Forward Current | | 45 | A | $V_{GS} = -4\text{ V}, T_c = 25^\circ\text{C}$ | |
| $I_{S,pulse}$ | Diode pulse Current | | 251 | A | $V_{GS} = -4\text{ V}$, pulse width t_p limited by T_{Jmax} | |
| t_{rr} | Reverse Recover time | 13 | | ns | $V_{GS} = -4\text{ V}, I_{SD} = 33.5\text{ A}, V_R = 400\text{ V}$ $dif/dt = 5665\text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$ | |
| Q_{rr} | Reverse Recovery Charge | 274 | | nC | | |
| I_{rrm} | Peak Reverse Recovery Current | 37 | | A | | |
| t_{rr} | Reverse Recover time | 16 | | ns | $V_{GS} = -4\text{ V}, I_{SD} = 33.5\text{ A}, V_R = 400\text{ V}$ $dif/dt = 1630\text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$ | |
| Q_{rr} | Reverse Recovery Charge | 164 | | nC | | |
| I_{rrm} | Peak Reverse Recovery Current | 17 | | A | | |

Thermal Characteristics

| Symbol | Parameter | Typ. | Unit | Test Conditions | Note |
|-----------------|---|------|------|-----------------|---------|
| $R_{\theta JC}$ | Thermal Resistance from Junction to Case | 0.46 | °C/W | | Fig. 21 |
| $R_{\theta JA}$ | Thermal Resistance From Junction to Ambient | 40 | | | |

Typical Performance

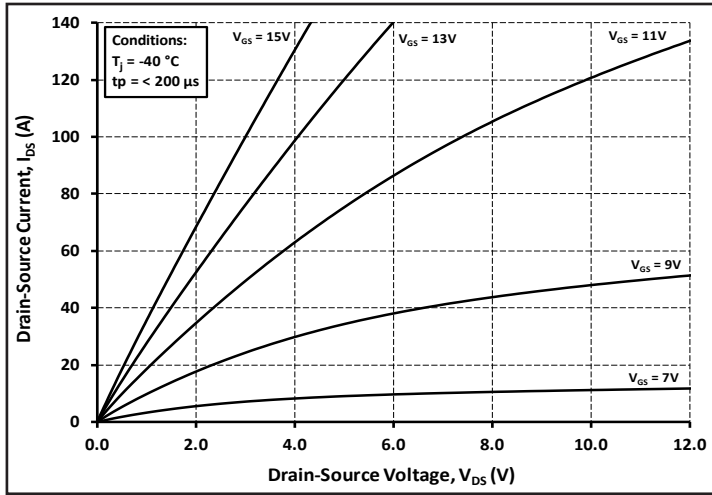


Figure 1. Output Characteristics $T_j = -40\text{ }^\circ\text{C}$

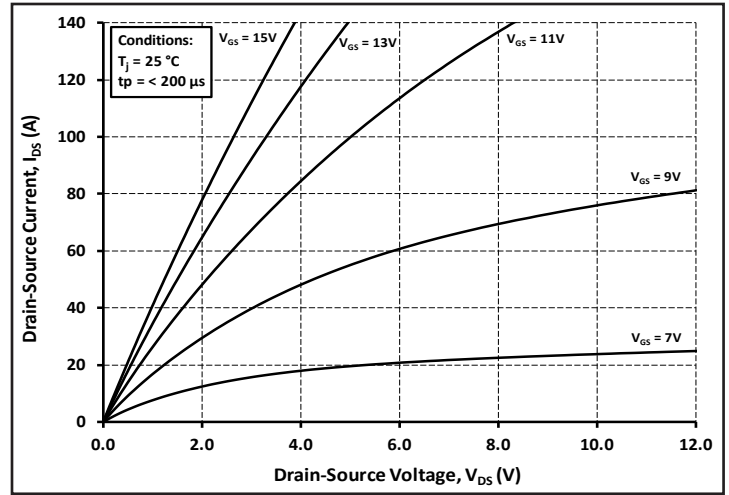


Figure 2. Output Characteristics $T_j = 25\text{ }^\circ\text{C}$

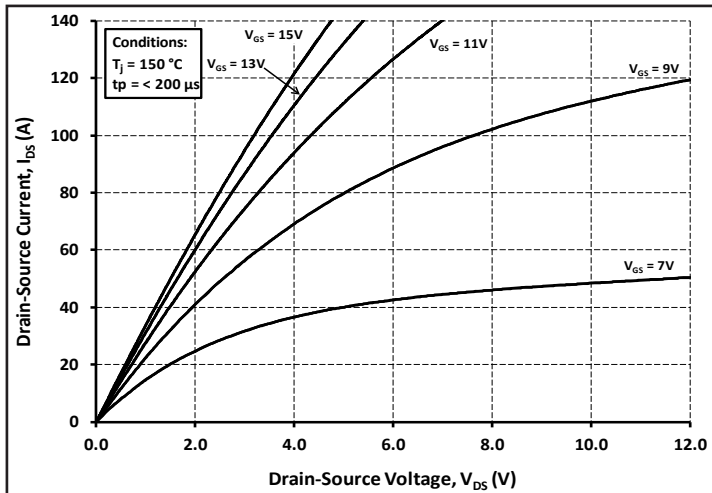


Figure 3. Output Characteristics $T_j = 150\text{ }^\circ\text{C}$

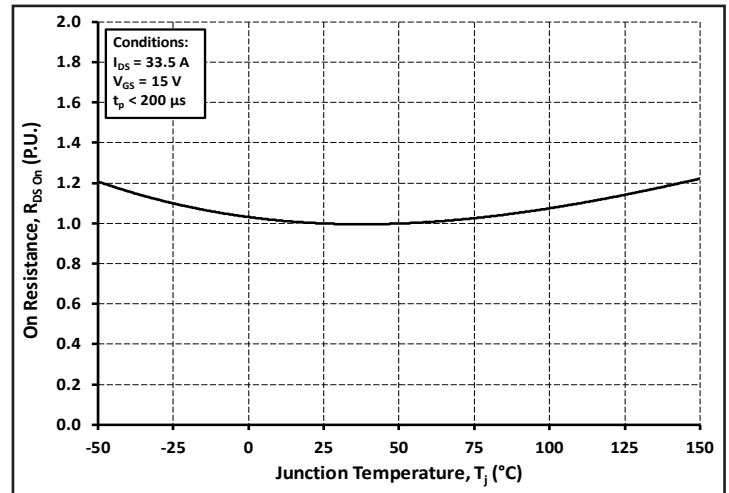


Figure 4. Normalized On-Resistance vs. Temperature

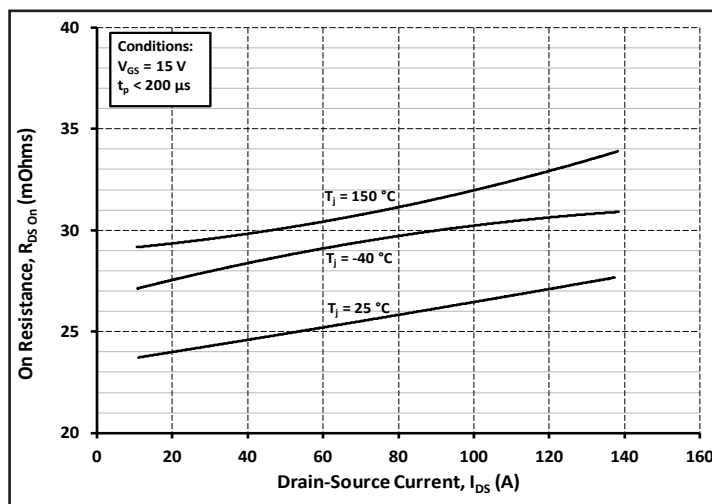


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

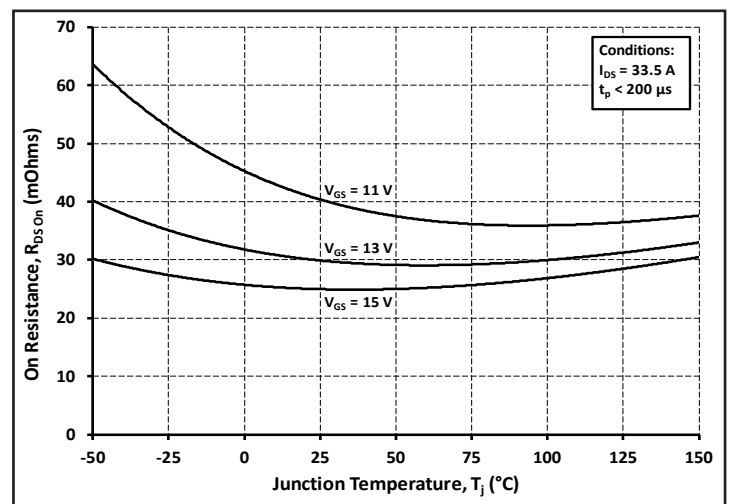


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

Typical Performance

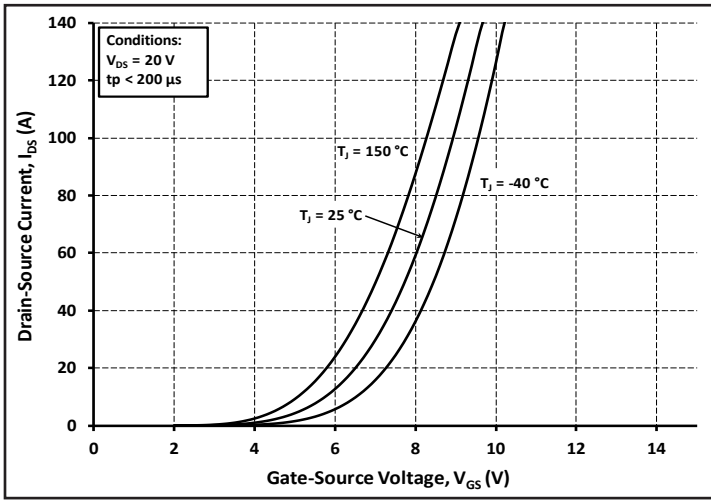


Figure 7. Transfer Characteristic for Various Junction Temperatures

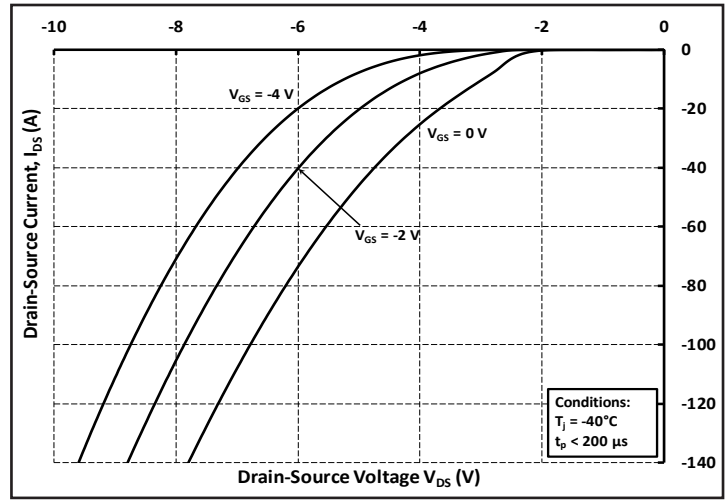


Figure 8. Body Diode Characteristic at -40 °C

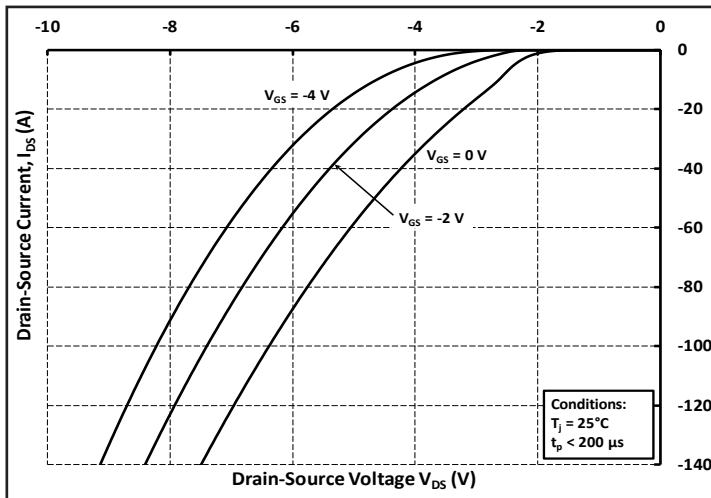


Figure 9. Body Diode Characteristic at 25 °C

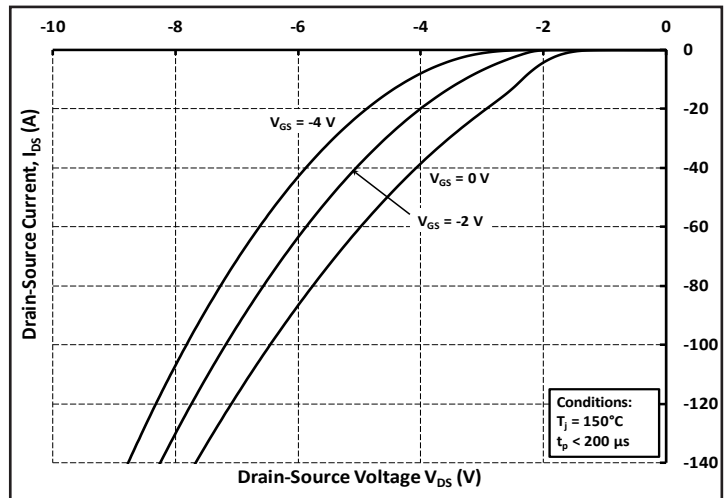


Figure 10. Body Diode Characteristic at 150 °C

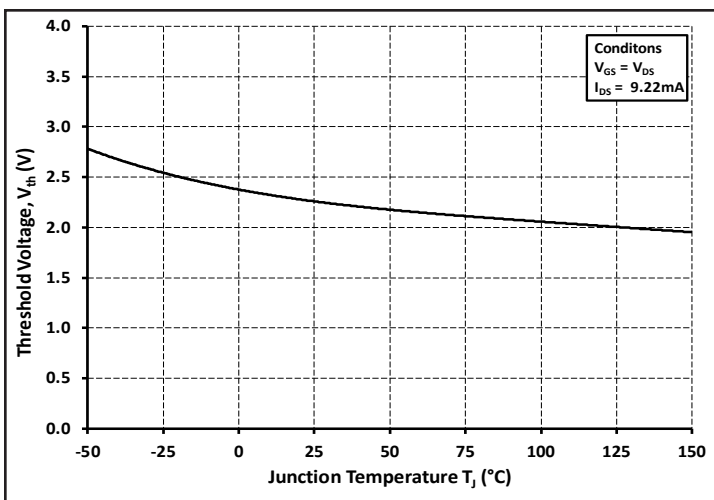


Figure 11. Threshold Voltage vs. Temperature

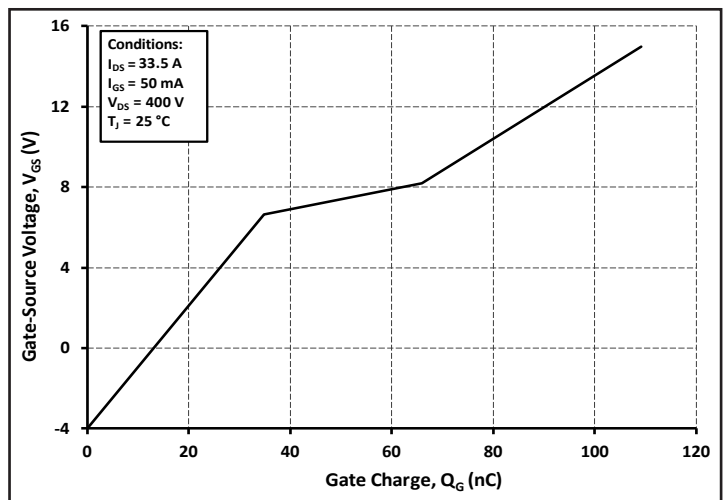


Figure 12. Gate Charge Characteristics

Typical Performance

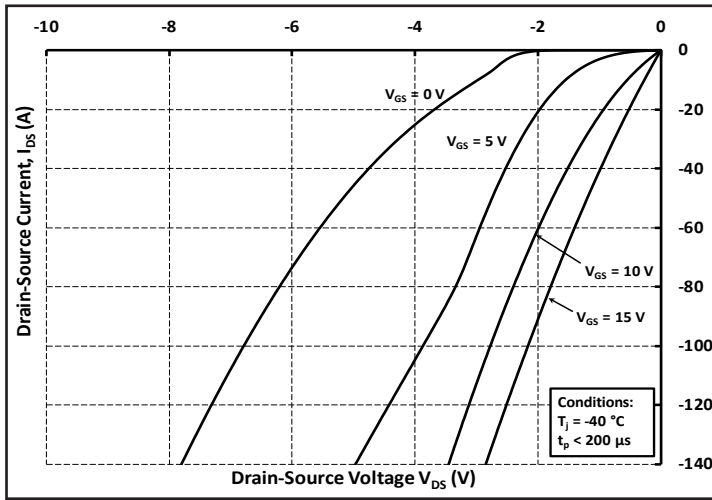


Figure 13. 3rd Quadrant Characteristic at -40 °C

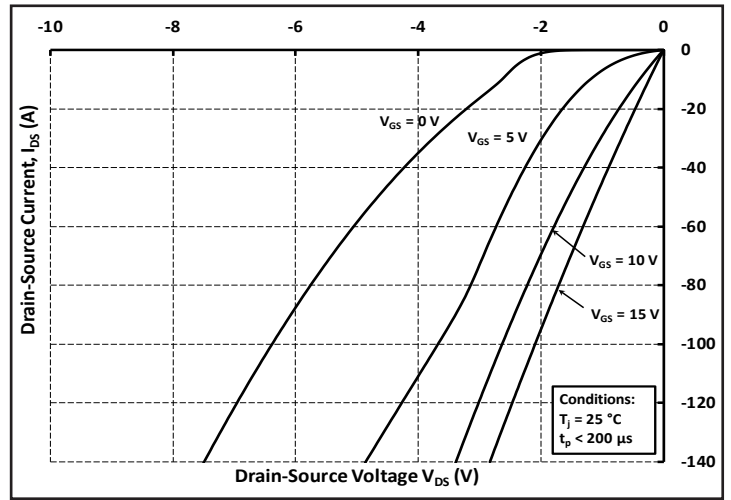


Figure 14. 3rd Quadrant Characteristic at 25 °C

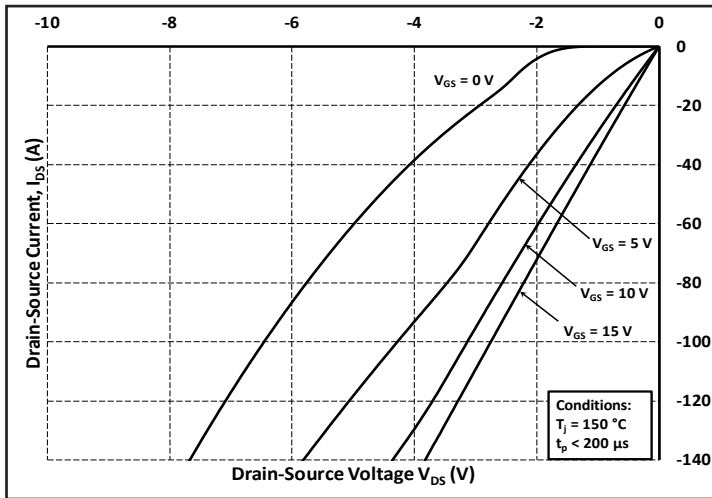


Figure 15. 3rd Quadrant Characteristic at 150 °C

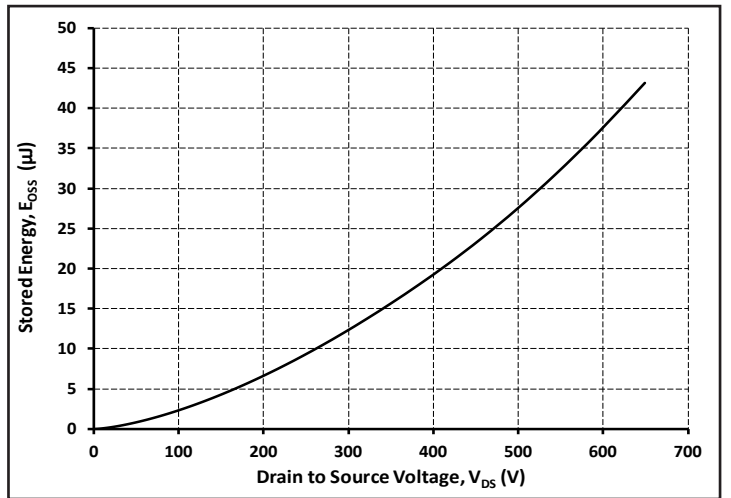


Figure 16. Output Capacitor Stored Energy

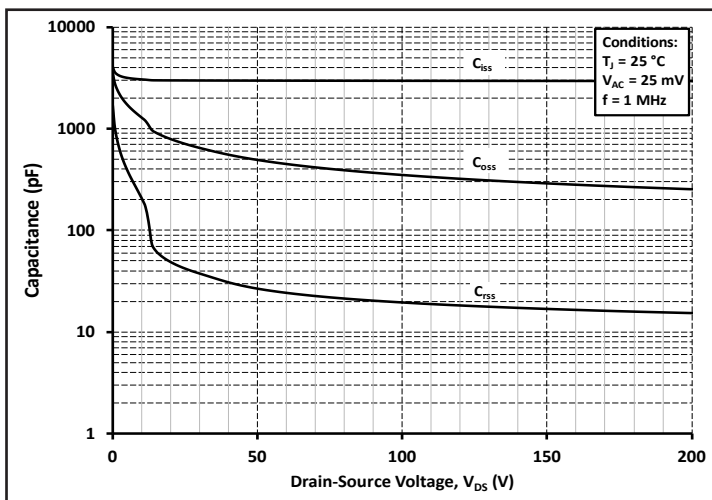


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

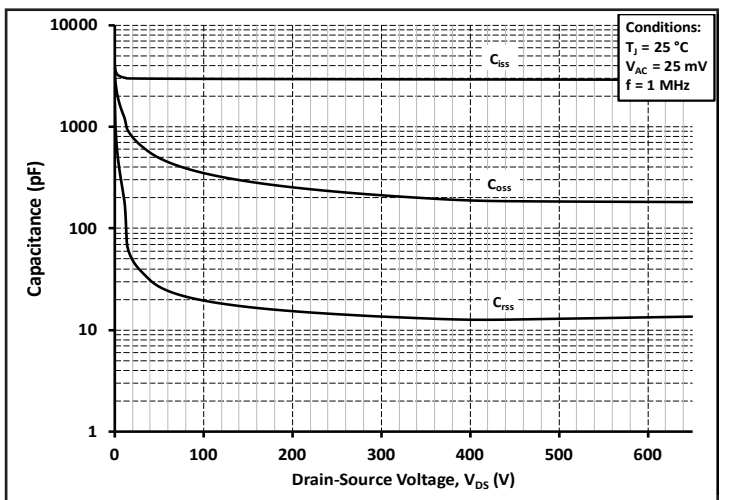


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 600V)

Typical Performance

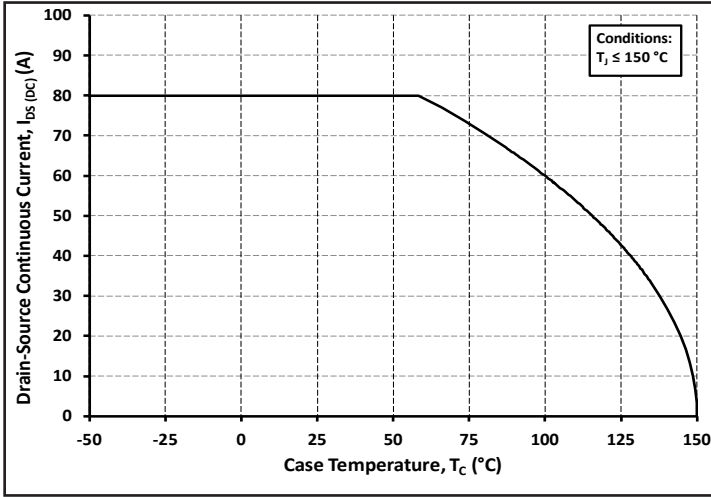


Figure 19. Continuous Drain Current Derating vs. Case Temperature

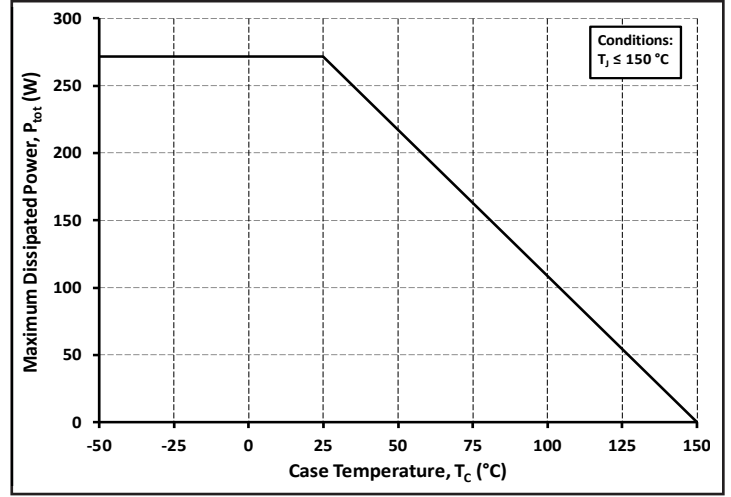


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

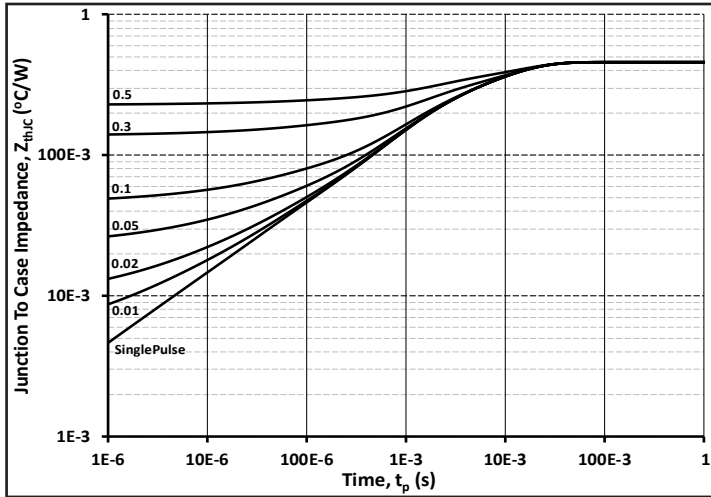


Figure 21. Transient Thermal Impedance (Junction - Case)

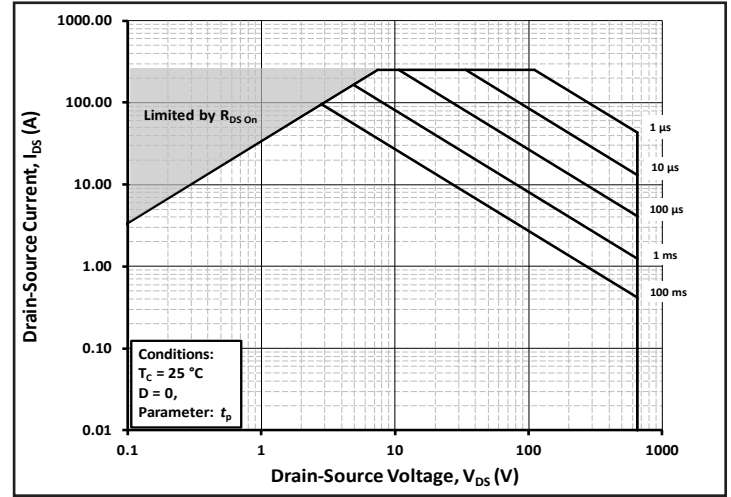


Figure 22. Safe Operating Area

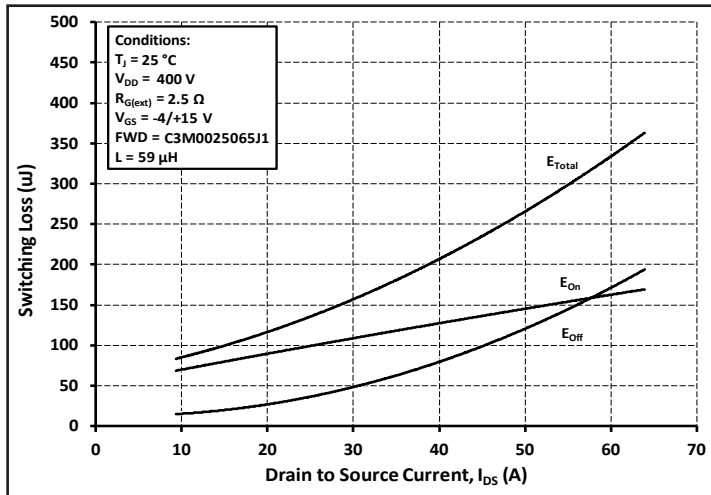


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ($V_{DD} = 400V$)

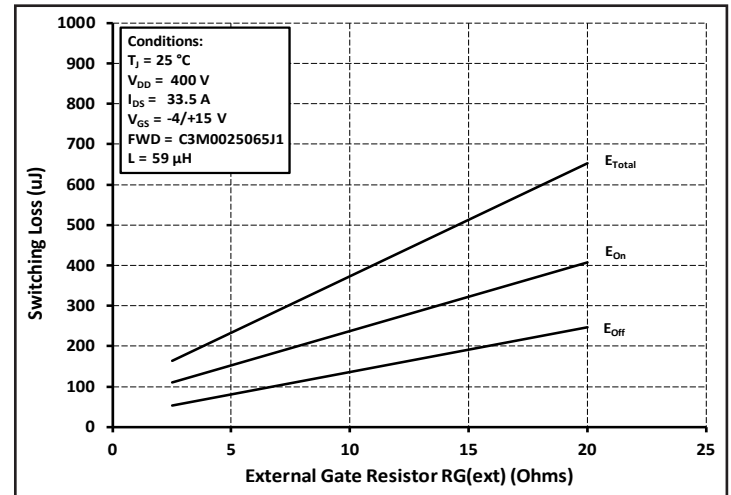


Figure 24. Clamped Inductive Switching Energy vs. $R_{G(ext)}$

Typical Performance

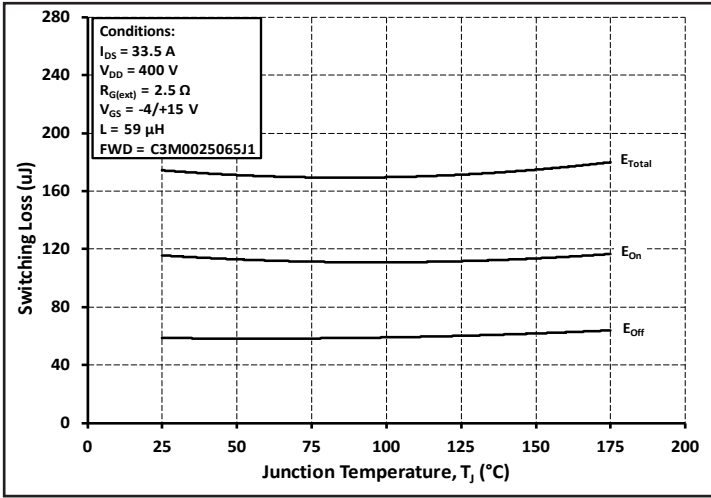


Figure 25. Clamped Inductive Switching Energy vs. Temperature

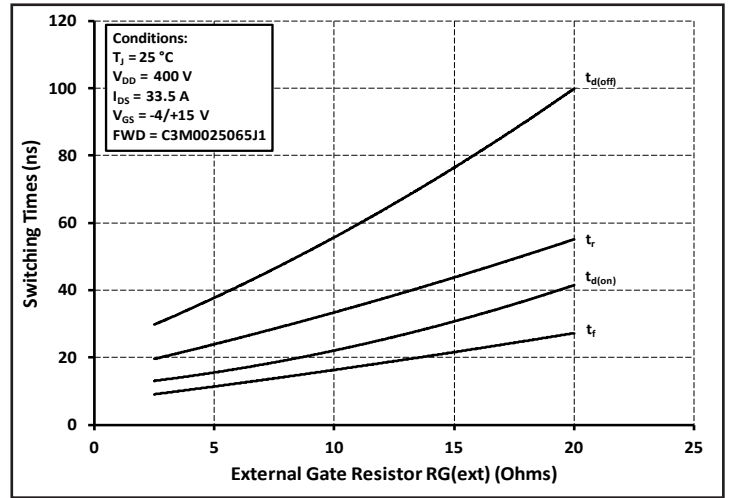


Figure 26. Switching Times vs $R_{G(ext)}$

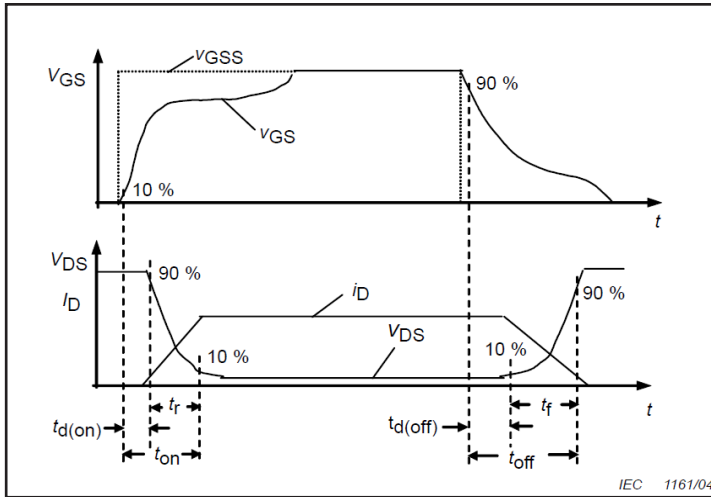


Figure 27. Switching Times Definition

Test Circuit Schematic

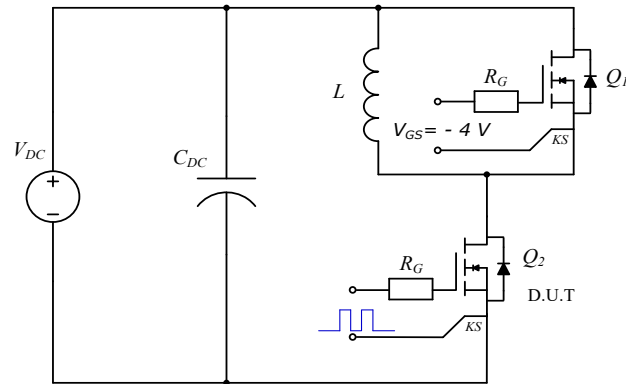
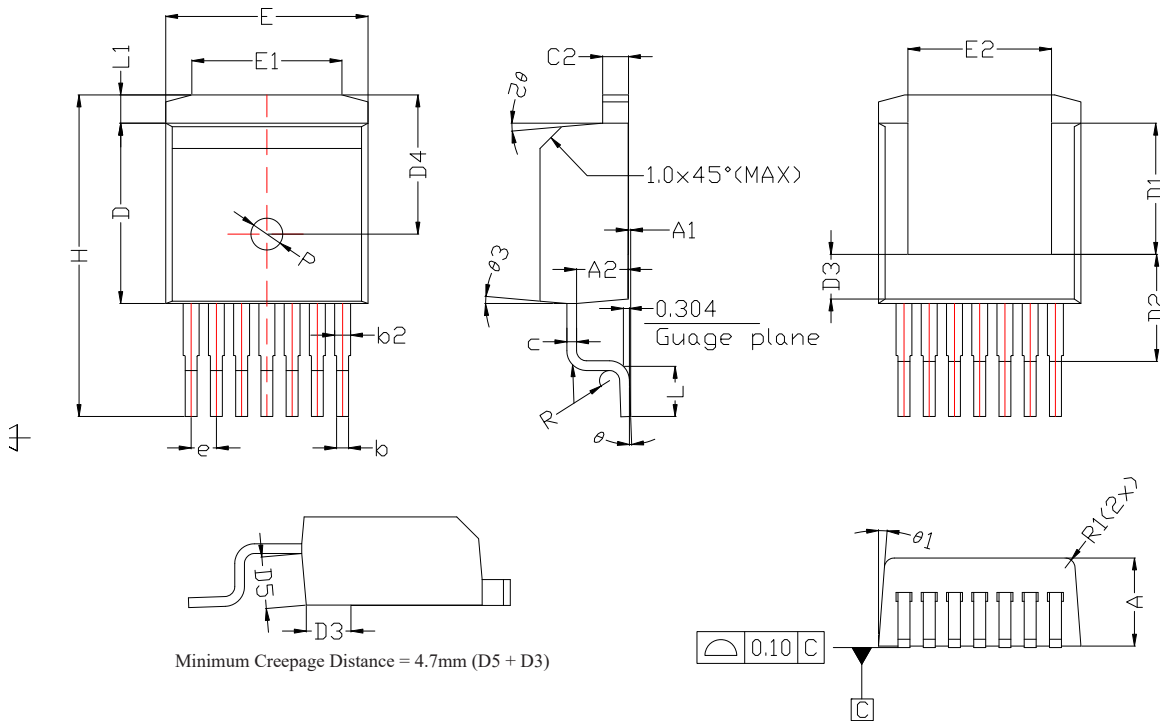


Figure 28. Clamped Inductive Switching Waveform Test Circuit

Note (3): Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode as shown above.

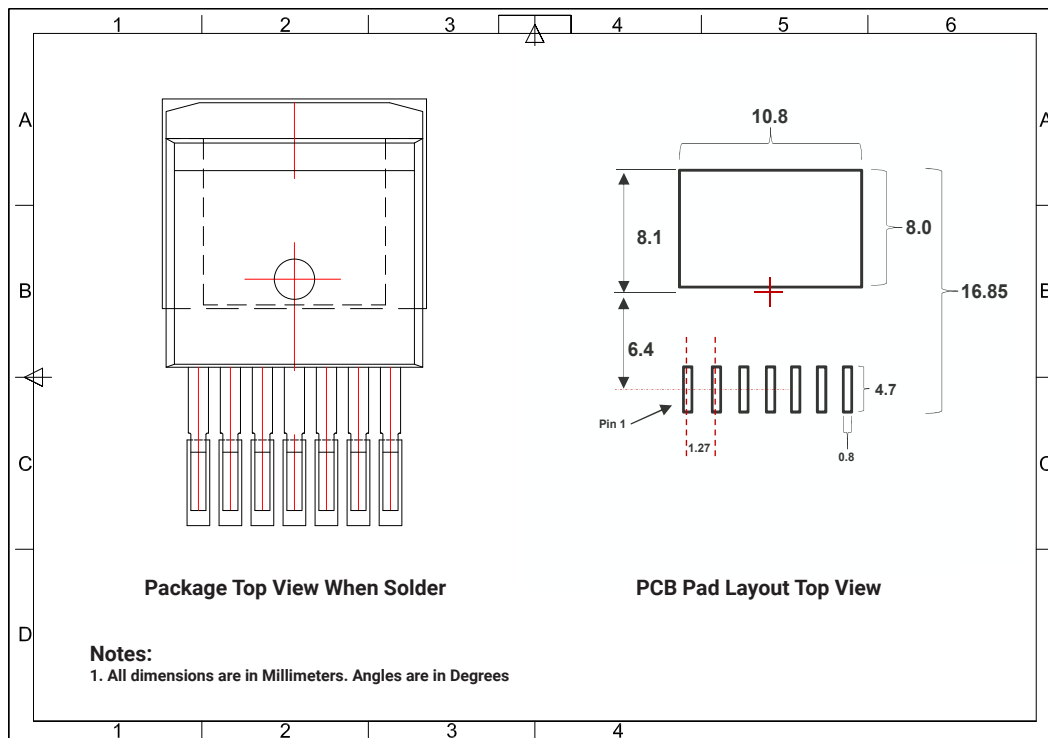
Package Dimensions

TO-263-7L XL



| DIM | MIN | MAX | TYP |
|-----|------------|--------|--------|
| D | 9.025 | 9.125 | 9.075 |
| E | 10.13 | 10.23 | 10.18 |
| A | 4.30 | 4.57 | 4.435 |
| H | 15.043 | 17.313 | 16.178 |
| D1 | 6.50 | 6.70 | 6.60 |
| E1 | 6.50 | 8.60 | 7.55 |
| D2 | 5.39 REF. | | |
| E2 | 6.778 | 7.665 | 7.223 |
| D3 | 2.148 | 2.248 | |
| D4 | 7.00 REF. | | |
| D5 | 2.555 | 2.605 | |
| A1 | 0 | 0.25 | 0.125 |
| A2 | 2.595 REF. | | |
| e | 1.27 TYP. | | |
| L | 2.324 | 2.70 | 2.512 |
| b | 0.50 | 0.70 | 0.60 |
| L1 | 0.968 | 1.868 | 1.418 |
| b2 | 0.60 | 1.00 | 0.80 |
| C2 | 1.17 | 1.37 | 1.27 |
| c | 0.281 | 0.481 | 0.381 |
| R | 0.506 REF. | | |
| R1 | 0.50 REF. | | |
| P | ø1.60 REF. | | |
| ø | 0° | 8° | 4° |
| ø1 | 4.5° | 5.5° | 5° |
| ø2 | 4° | 6° | 5° |
| ø3 | 4° | 6° | 5° |

- NOTES:
1. ALL DIMENSIONS ARE IN MILLIMETER. ANGLES ARE IN DEGREE.
 2. DIMENSION "D" DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSIONS. INTERLEAD FLASH SHALL NOT EXCEED 0.50 MM PER SIDE. DIMENSION "E" DOES NOT INCLUDE MOLD FLASH, GATE BURRS, THE GATE BURRS SHALL NOT EXCEED 0.30MM.
 3. THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.
 4. "b2" DIMENSION DON'T INCLUDE DAMBAR PROTRUSION.
 5. THE VOID SHOULD BE CONTROL WITHIN 0.25MM.



- Notes:
1. All dimensions are in Millimeters. Angles are in Degrees